

<b>Notice of References Cited</b>	Application/Control No. 10/009,108	Applicant(s)/Patent Under Reexamination OYAMADA ET AL.	
	Examiner Martin J Angebranndt	Art Unit 1756	Page 1 of 1

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	U	Skoog and West, "Principles of Instrumental Analysis", (1980) pp. 174 and 175
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.